

Fluorescence microscopy – general overview

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- Transmitted light microscopy
- Fluorescence light microscopy

- Resolution
- PSF
- Widefield microscope
- Confocal microscope
- Super-resolution microscopy

Transmitted light microscopy

- light is passed from the illumination source on the opposite side of the specimen to the objective (illumination is **transmitted** through the specimen)
- **contrast-enhancing techniques** - sample preparation as well as optical tricks that generate intensity changes which are useful for observation and imaging

Contrast-Enhancing Techniques in Optical Microscopy

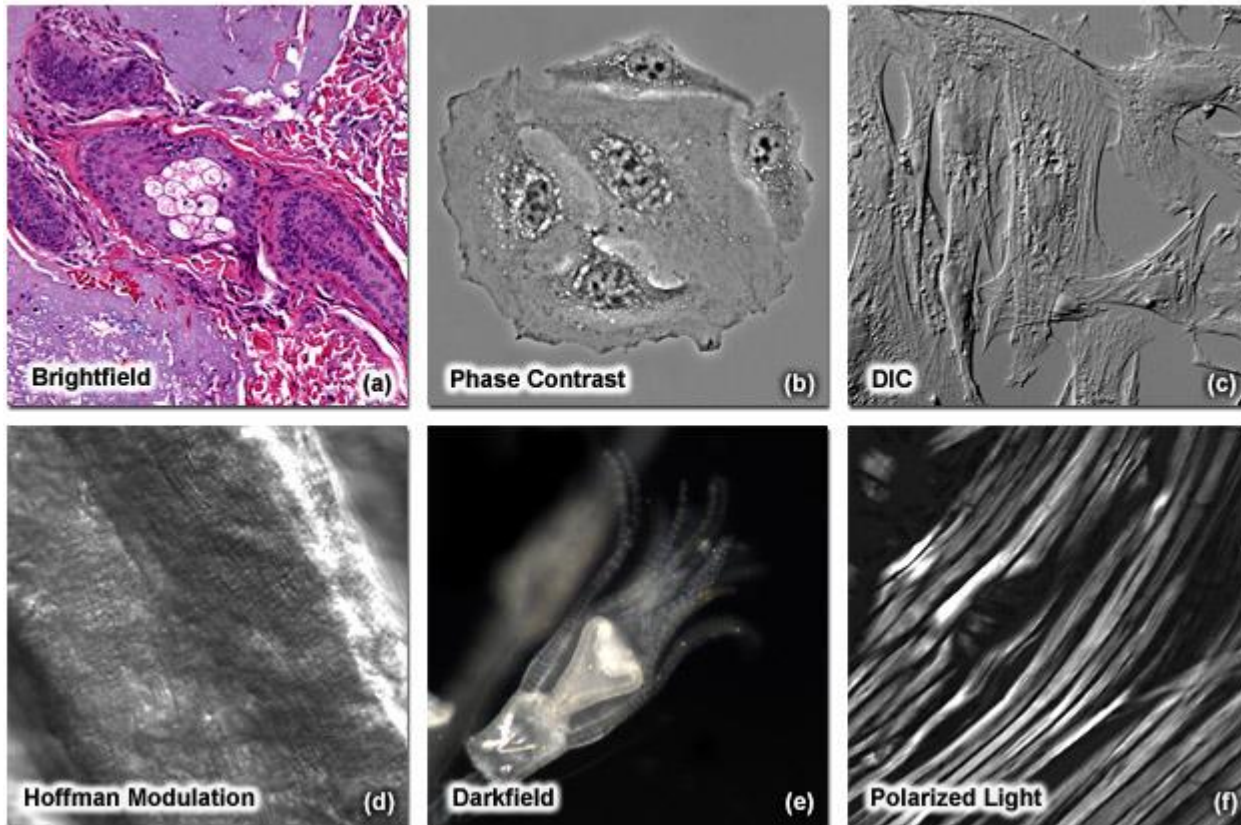
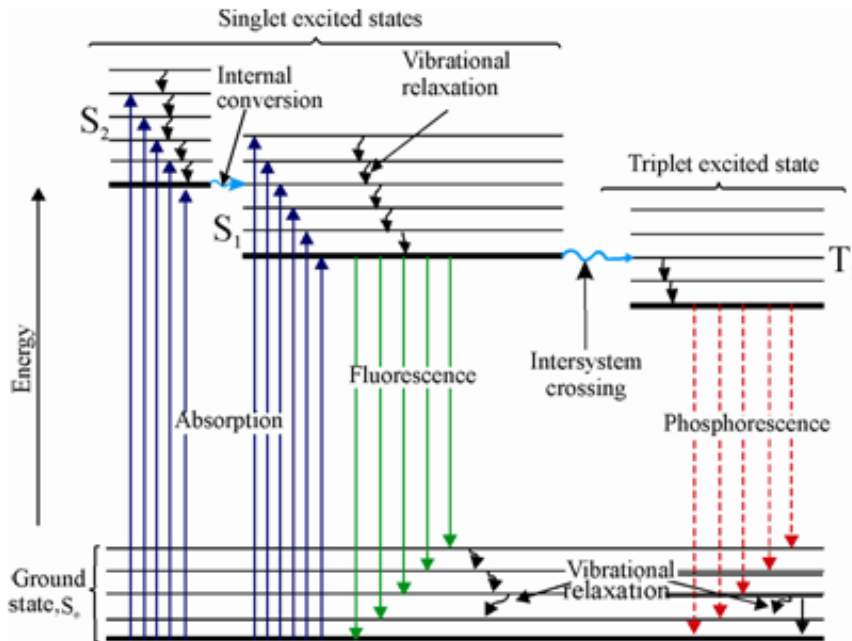


Figure 1

Fluorescence light microscopy

- **Luminiscence** - emission of light by a substance not resulting from heat, as a result of chemical reaction, electric current, absorption of photons, etc.
 - **Fluorescence** – a result of singlet-singlet electronic relaxation



Jablonski diagram



Fluorescence light microscopy

- **Luminiscence** - emission of light by a substance not resulting from heat, as a result of chemical reaction, electric current, absorption of photons, etc.
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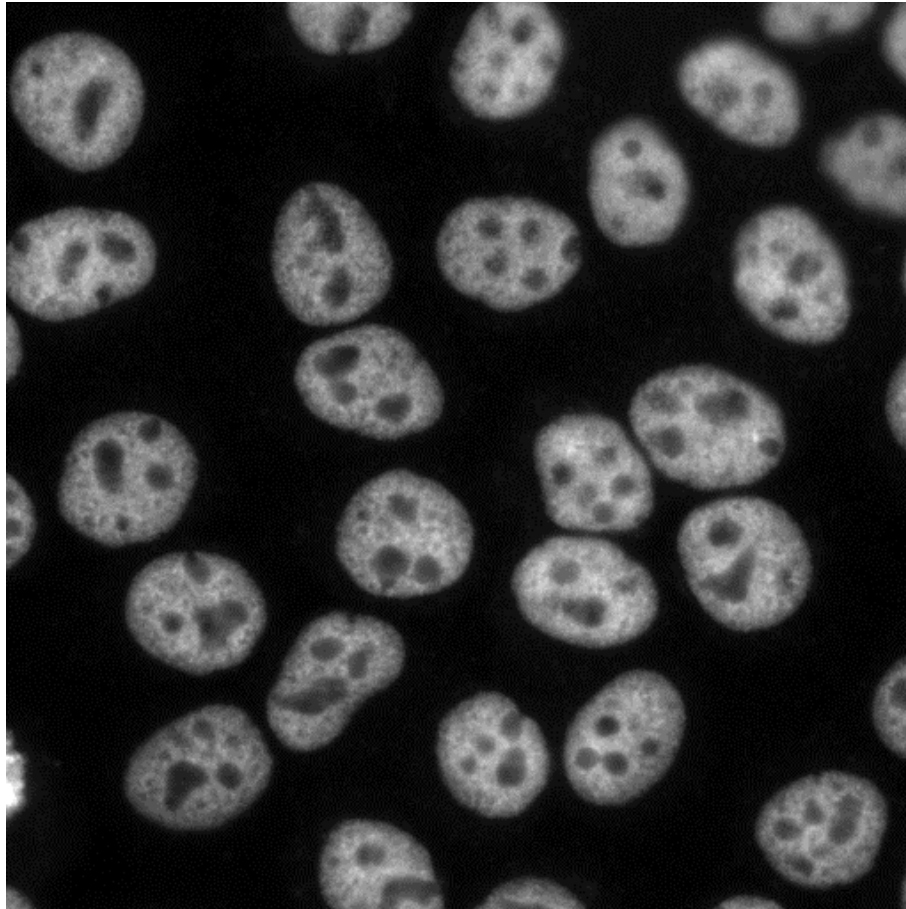
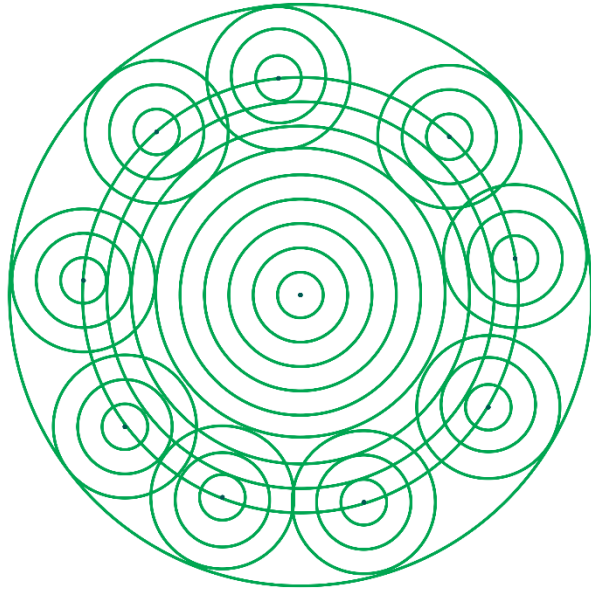


Image formation



Huygens principle

- every point on a wavefront is itself the source of spherical wavelets -> secondary sources of radiation
- wavefront of a propagating wave of light at any instant conforms to the envelope of spherical wavelets emanating from every point on the wavefront at the prior instant

Image formation

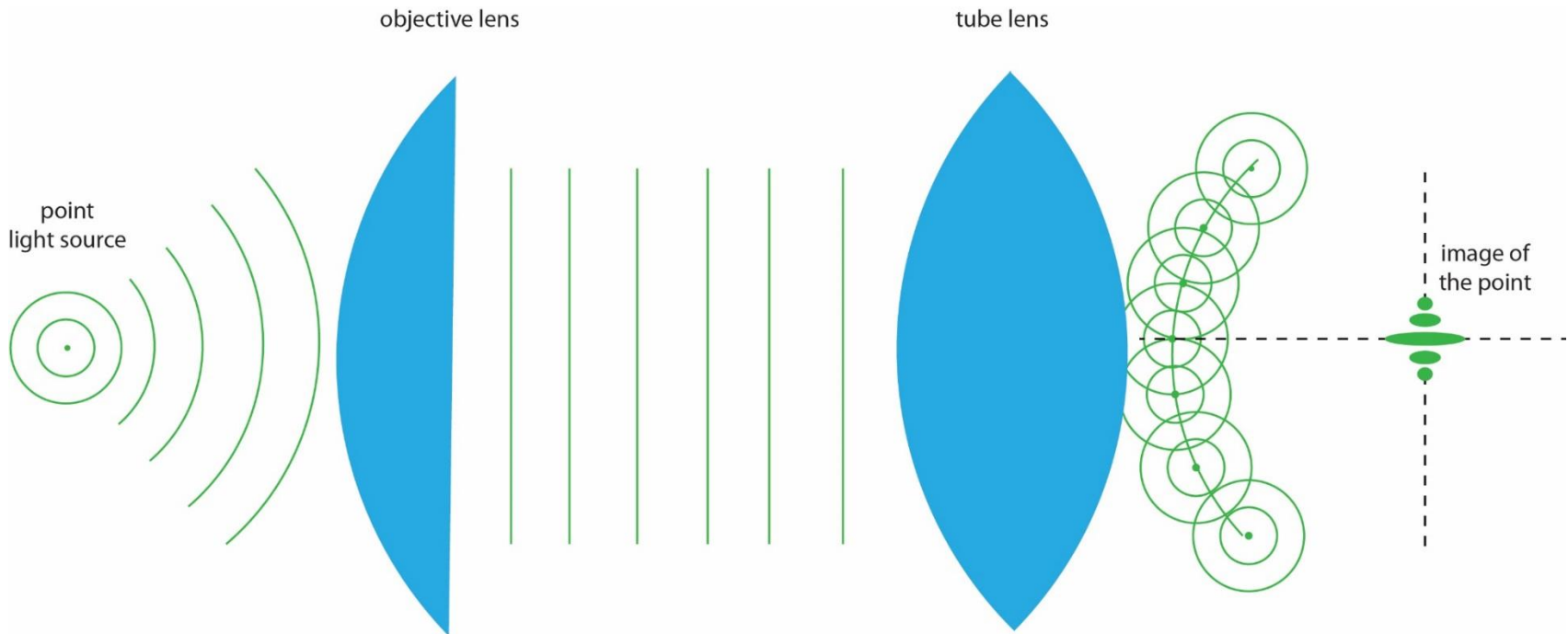
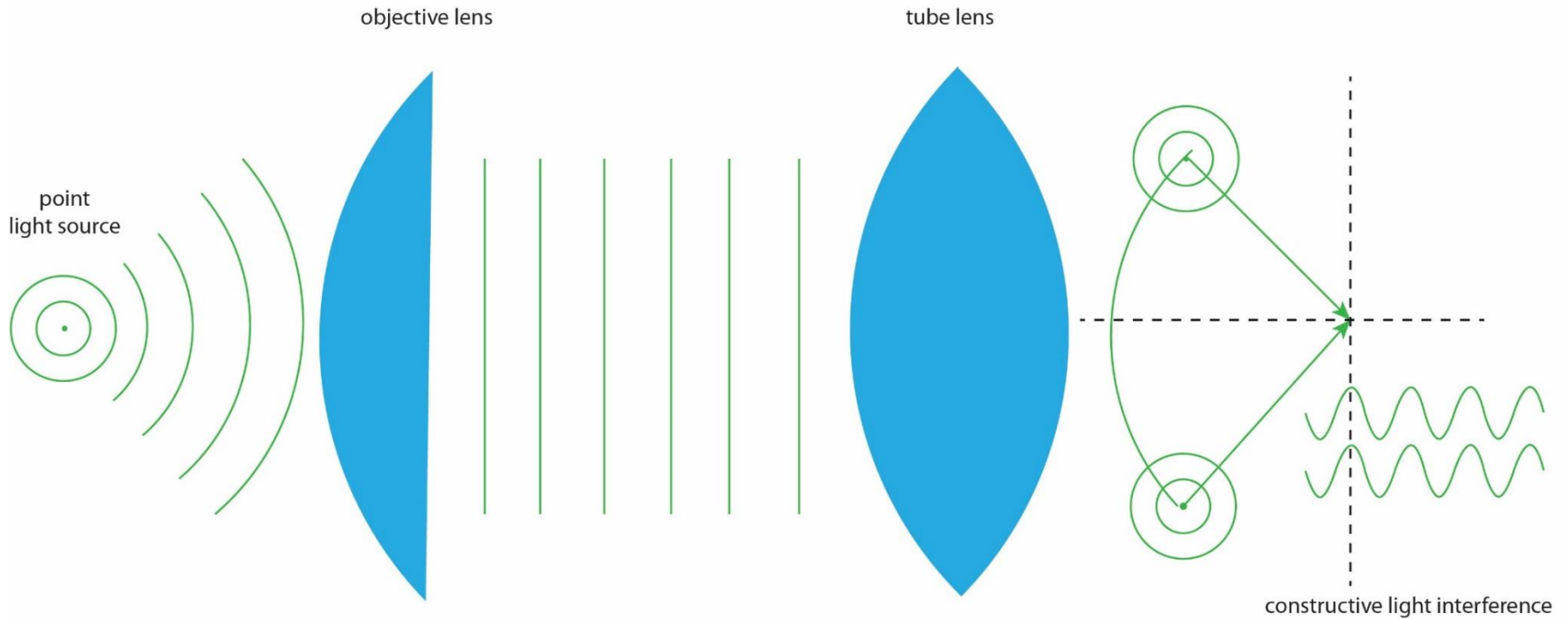


Image of a point light source

- focusing lens introduces the appropriate delays in the light paths (more delay in the center, and less in the borders)
- secondary sources

Image formation



In-phase contributions

- focus is at equal distance from all the secondary sources, all wave fronts from the secondary sources arrive in phase

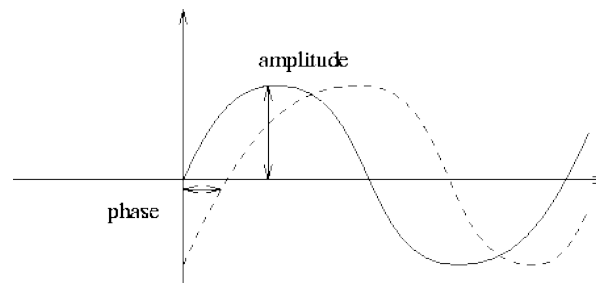
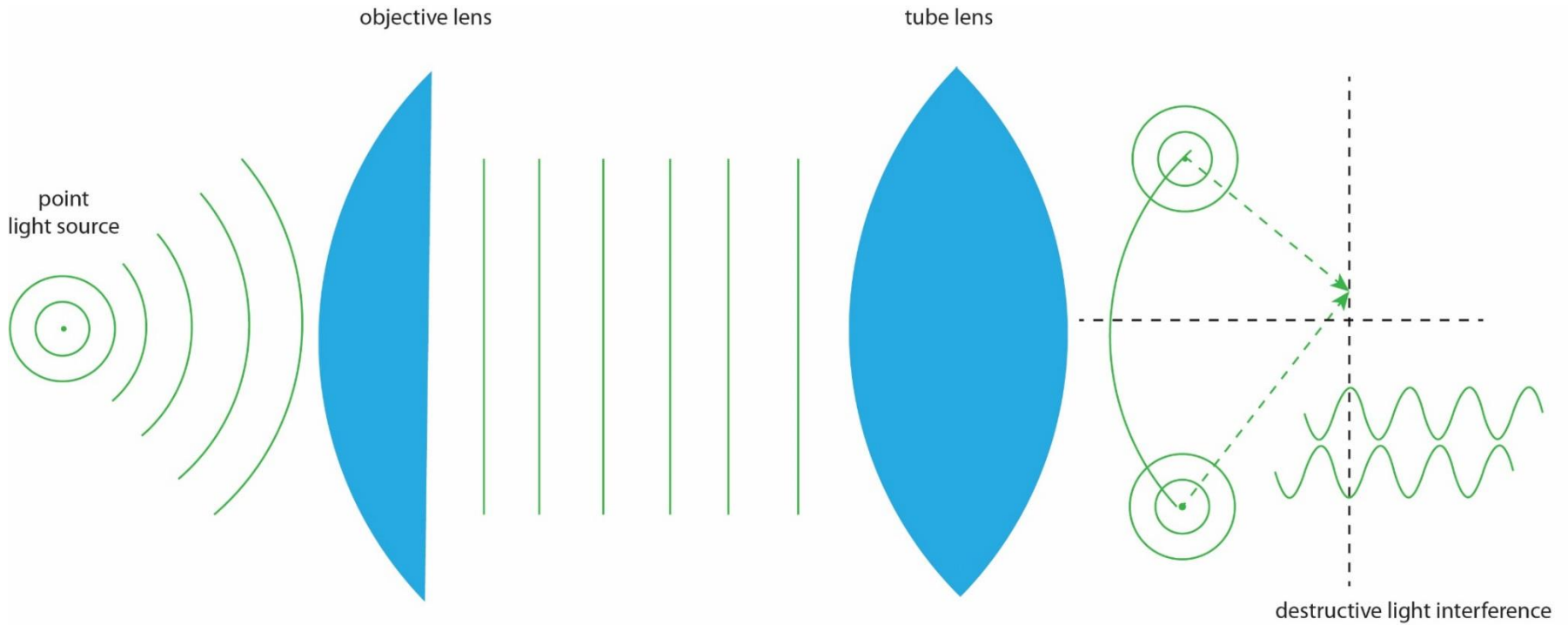


Image formation



Out-of-phase contributions

- resulting intensity decreases

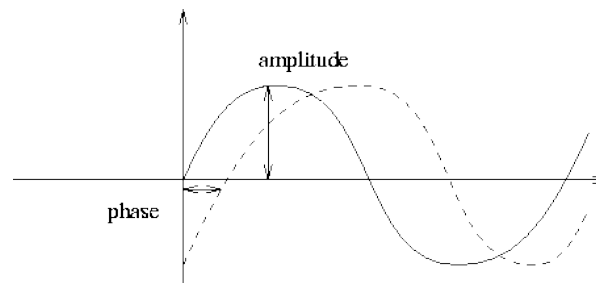
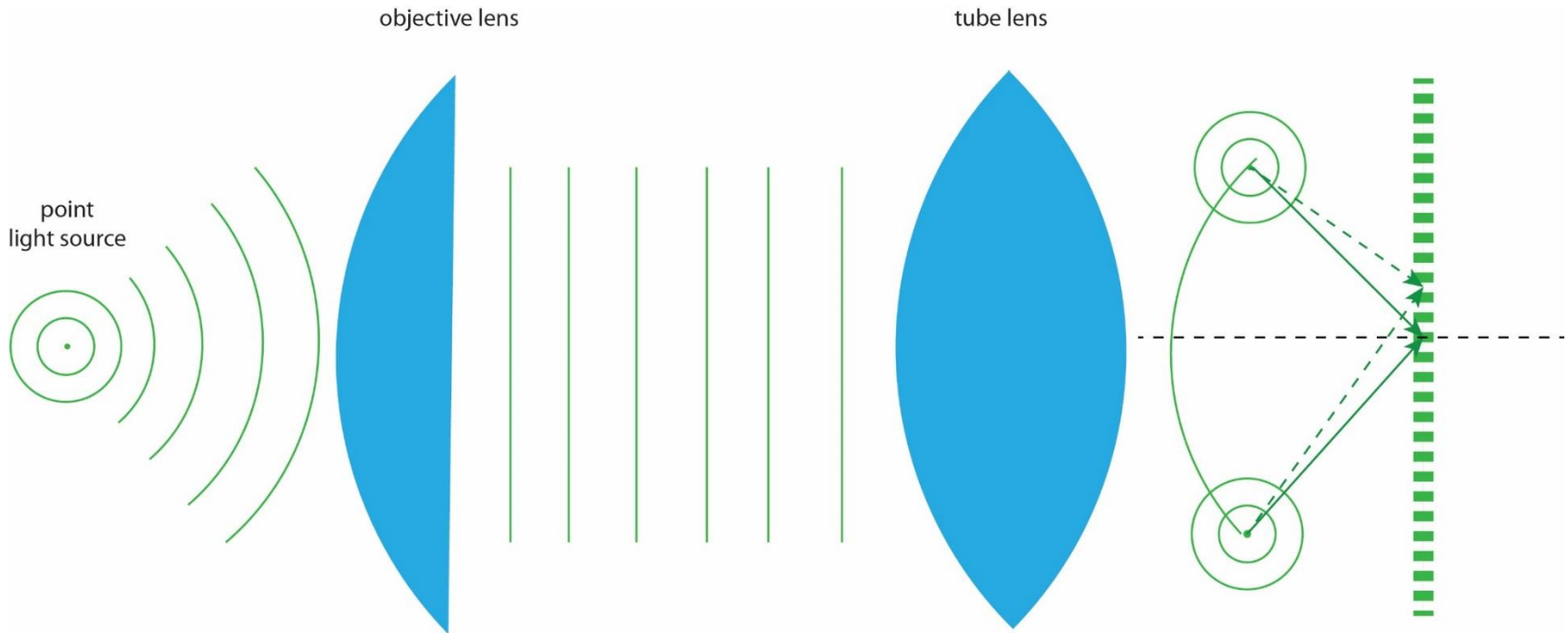
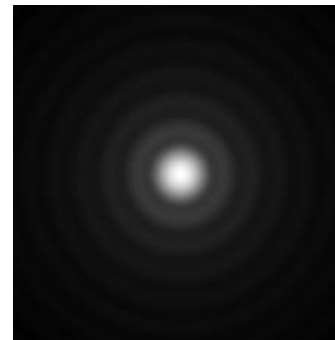


Image formation

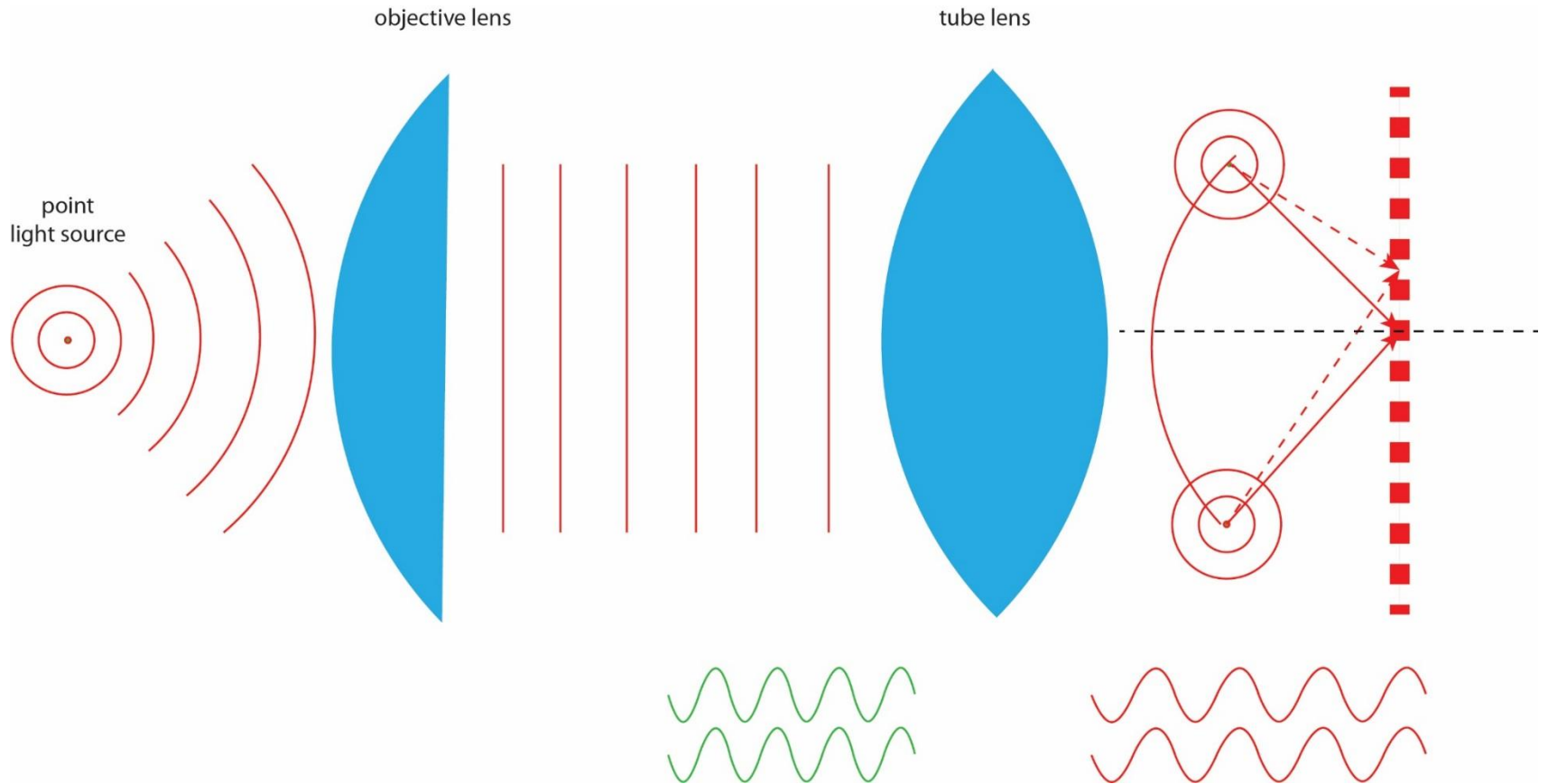


- constructive interference -> local maxima
- destructive interference -> local minima
- interference behavior described above is obtained similarly also along the optical axis (z)



- central Airy disk

Image formation



- intensity changes depend on the wavelength

Image formation

Numerical Aperture and Airy Disc Size

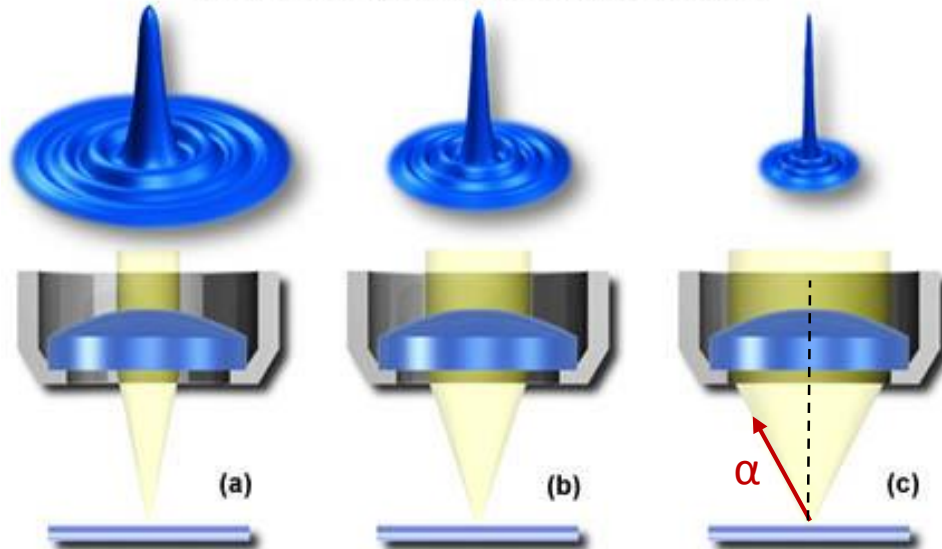


Figure 4

The amount of light that a lens can collect is measured by its **numerical aperture**

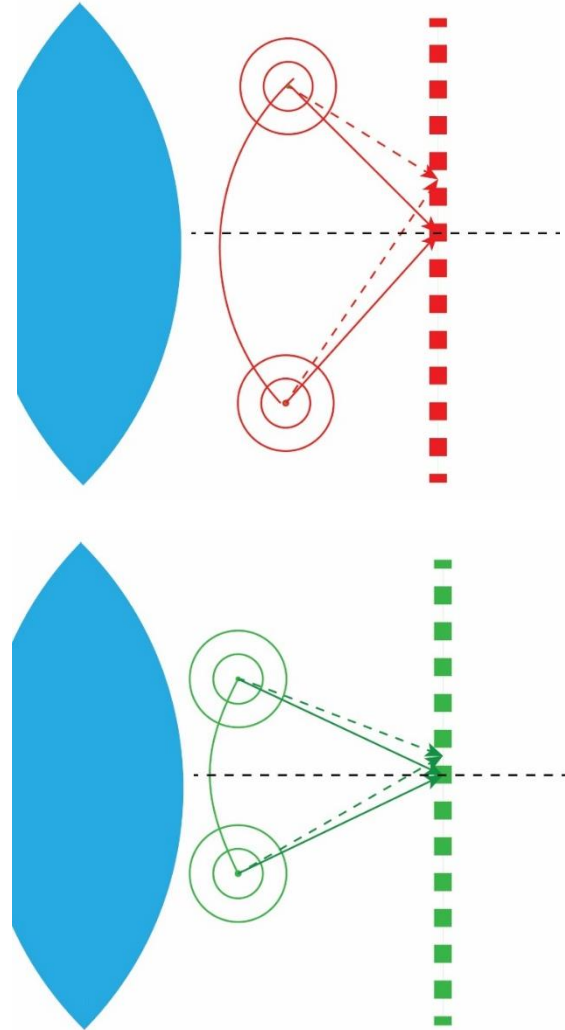
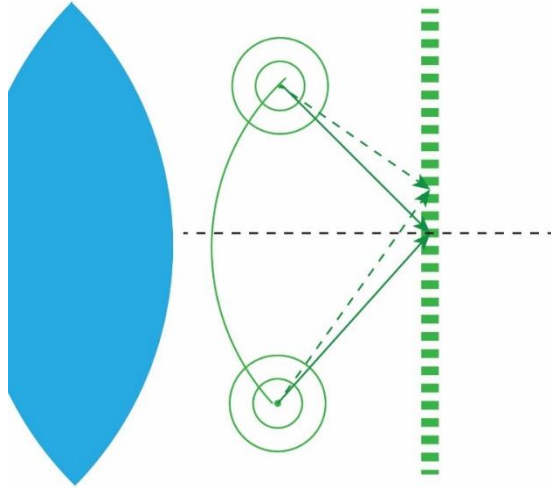
*maximal half-angle
of the cone of light*

$$NA = n \sin \alpha$$

refractive index

Resolution

$$r \sim \frac{\lambda}{NA}$$



Resolution

- *minimum resolvable distance* - the minimum distance between two distinguishable objects in an image

Abbe criterion

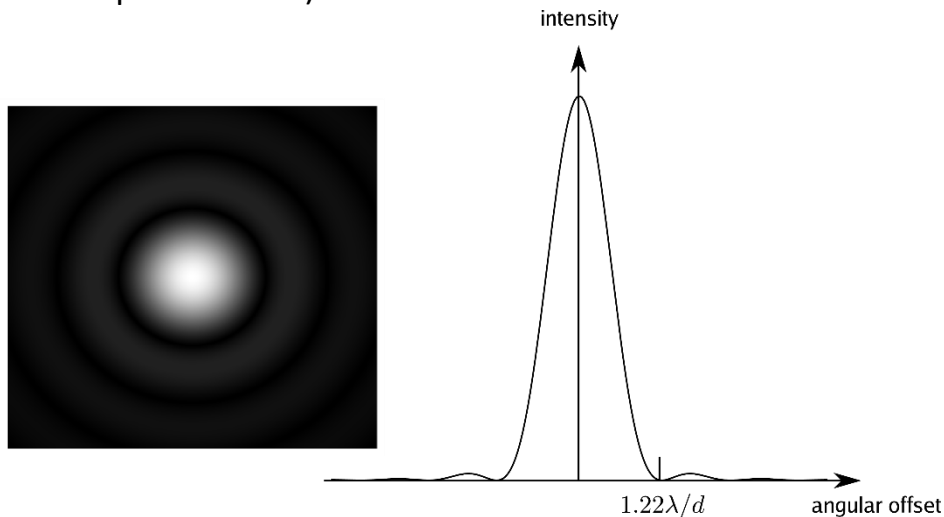
(radius of Airy disk)

$$r = \frac{0.5\lambda}{NA} = \frac{0.5\lambda}{n \sin\alpha}$$

Rayleigh criterion

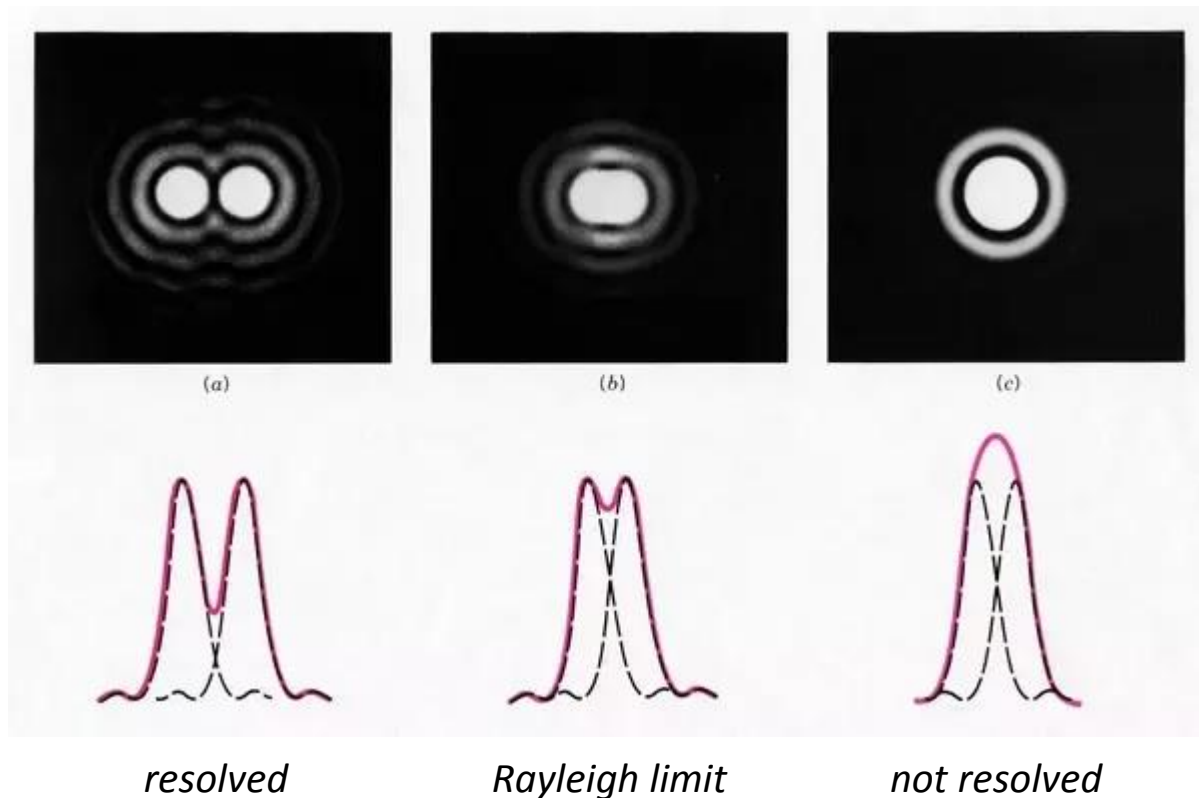
(principal diffraction maximum from one of the point sources overlaps with the first minimum from the other point source)

$$r = \frac{0.61\lambda}{NA} = \frac{0.61\lambda}{n \sin\alpha}$$



Resolution

- *minimum resolvable distance* - the minimum distance between two distinguishable objects in an image

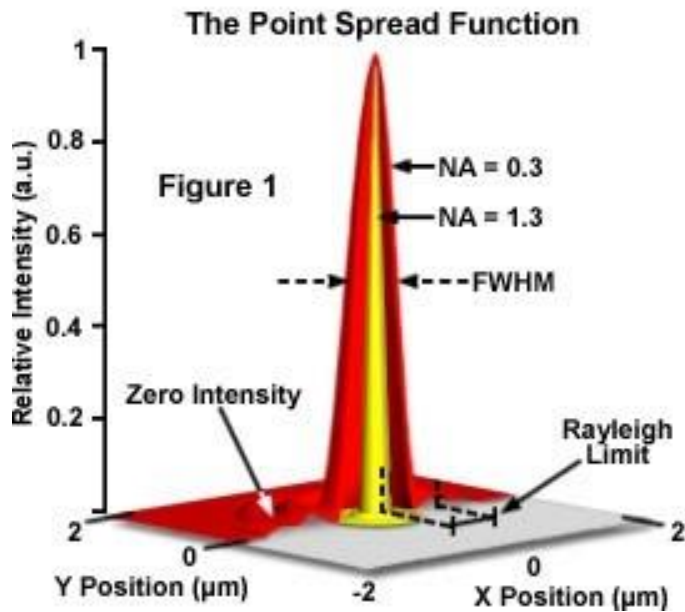


e.g. for GFP (emission 510 nm), $NA=1.4$ $r=222$ nm

-> *limited by diffraction*

PSF

Point spread function (PSF) describes the response of an imaging system to a point source or point object

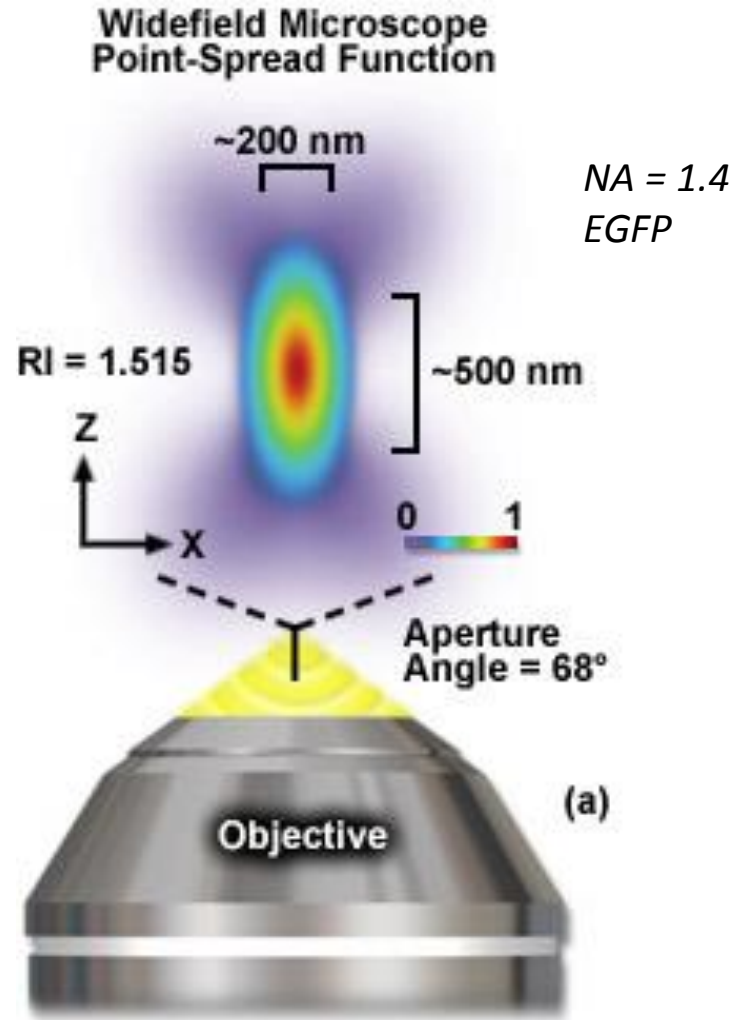
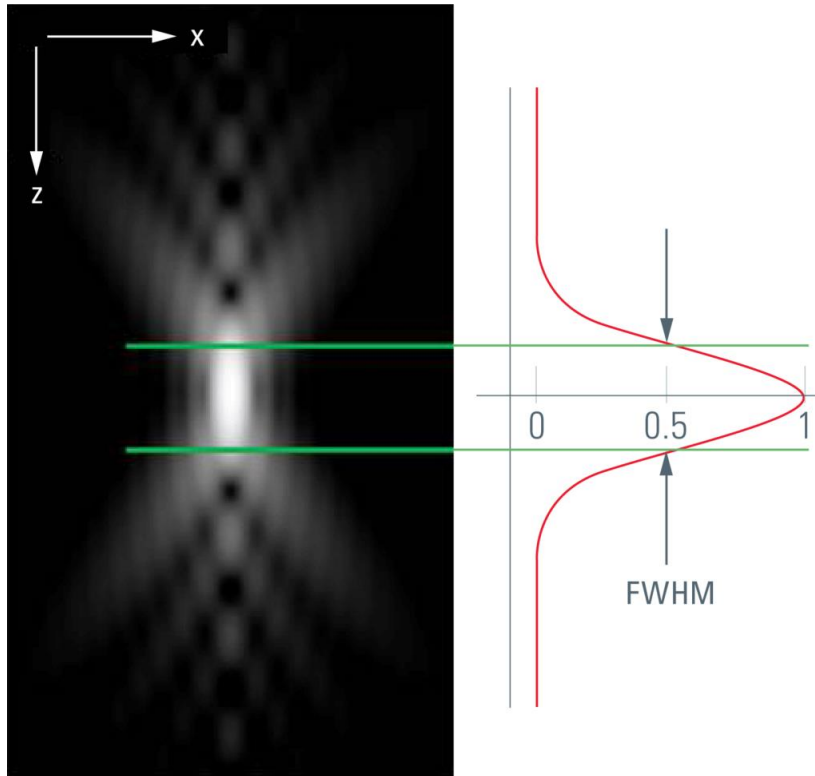


- lateral resolving power of an objective lens can be evaluated by measuring the size of the Airy disk (FWHM)

- different shapes in z depending on the instrument used -> **axial resolution**

- viewed in the x-y plane

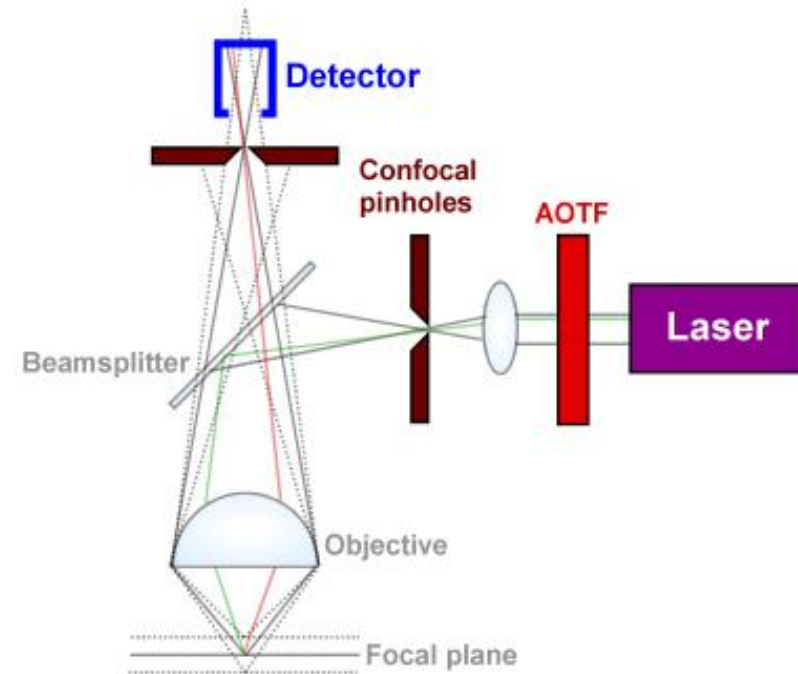
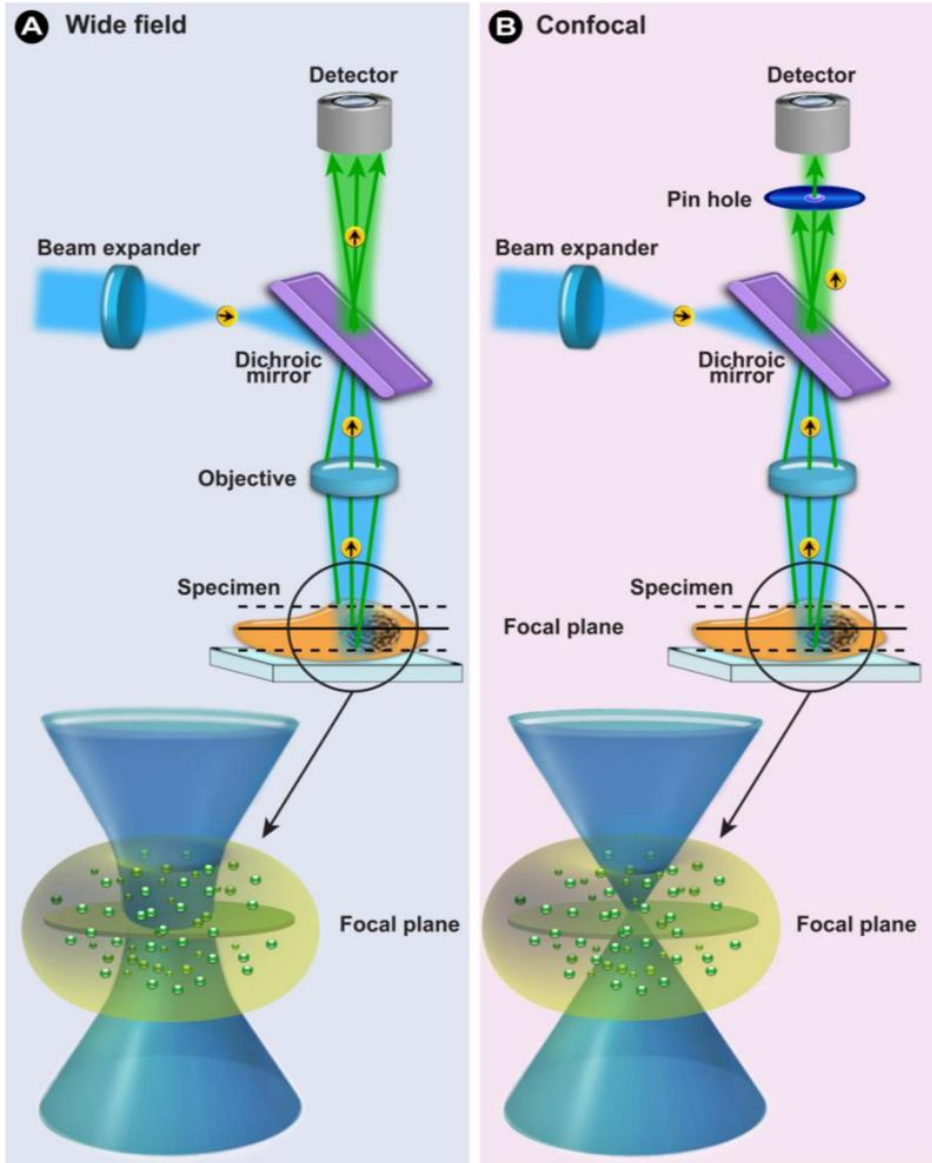
PSF



Axial resolution (Abbe):

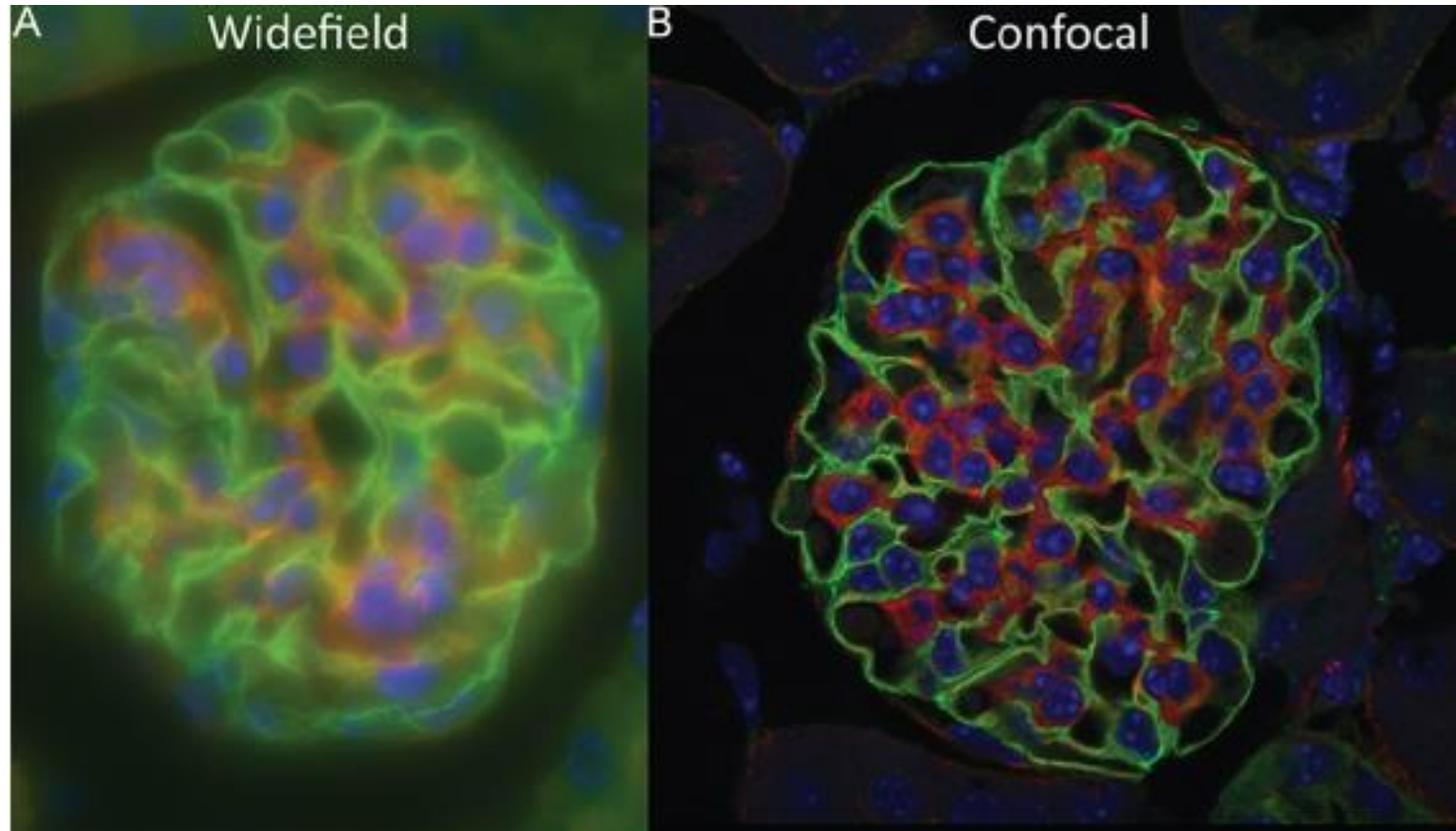
$$r_{axial} = \frac{2\lambda n}{NA^2}$$

Widefield vs. Confocal microscope

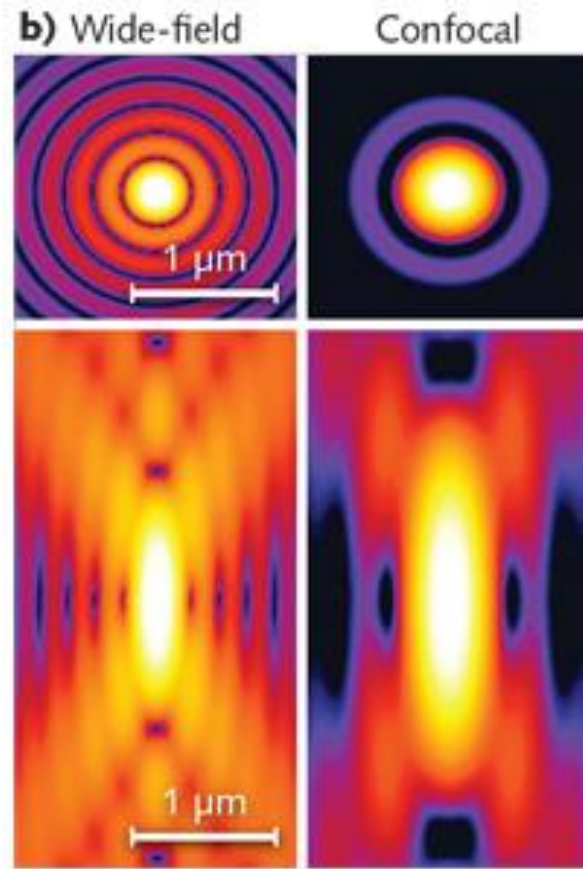


- dramatically increased contrast by removal of *out-of-focus* haze
- optical sectioning by the spot-scanning laser confocal microscope

Widefield vs. Confocal microscope



Widefield vs. Confocal microscope



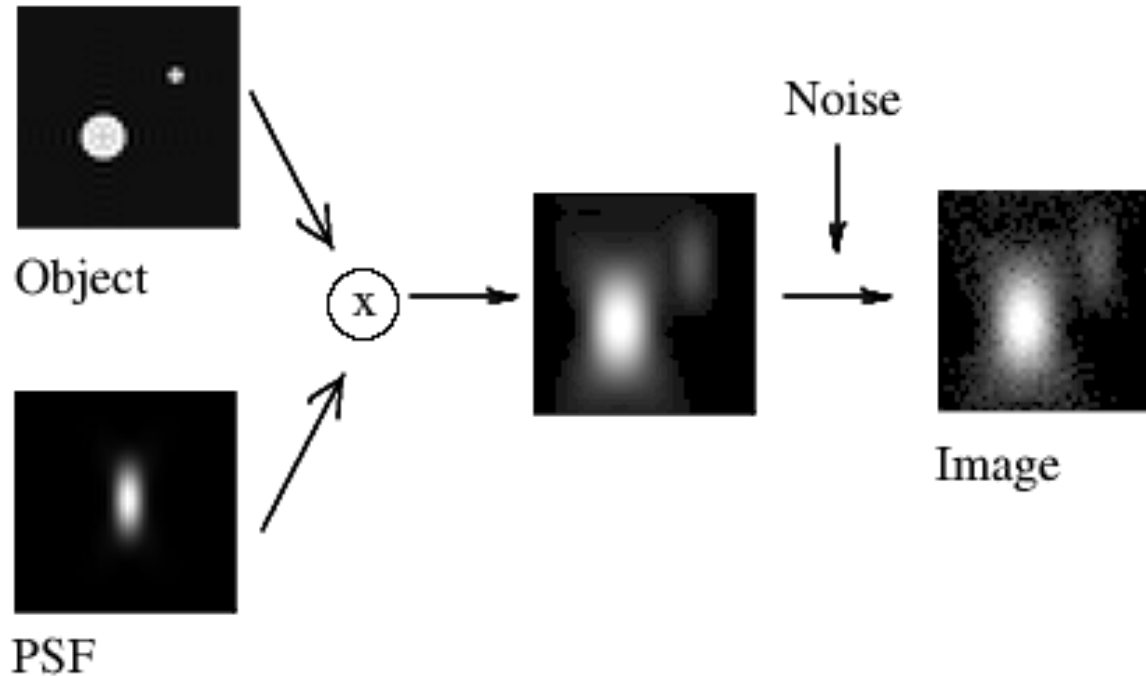
Confocal resolution:

$$r_{lateral} = \frac{0.4\lambda}{NA}$$

$$r_{axial} = \frac{1.4\lambda n}{NA^2}$$

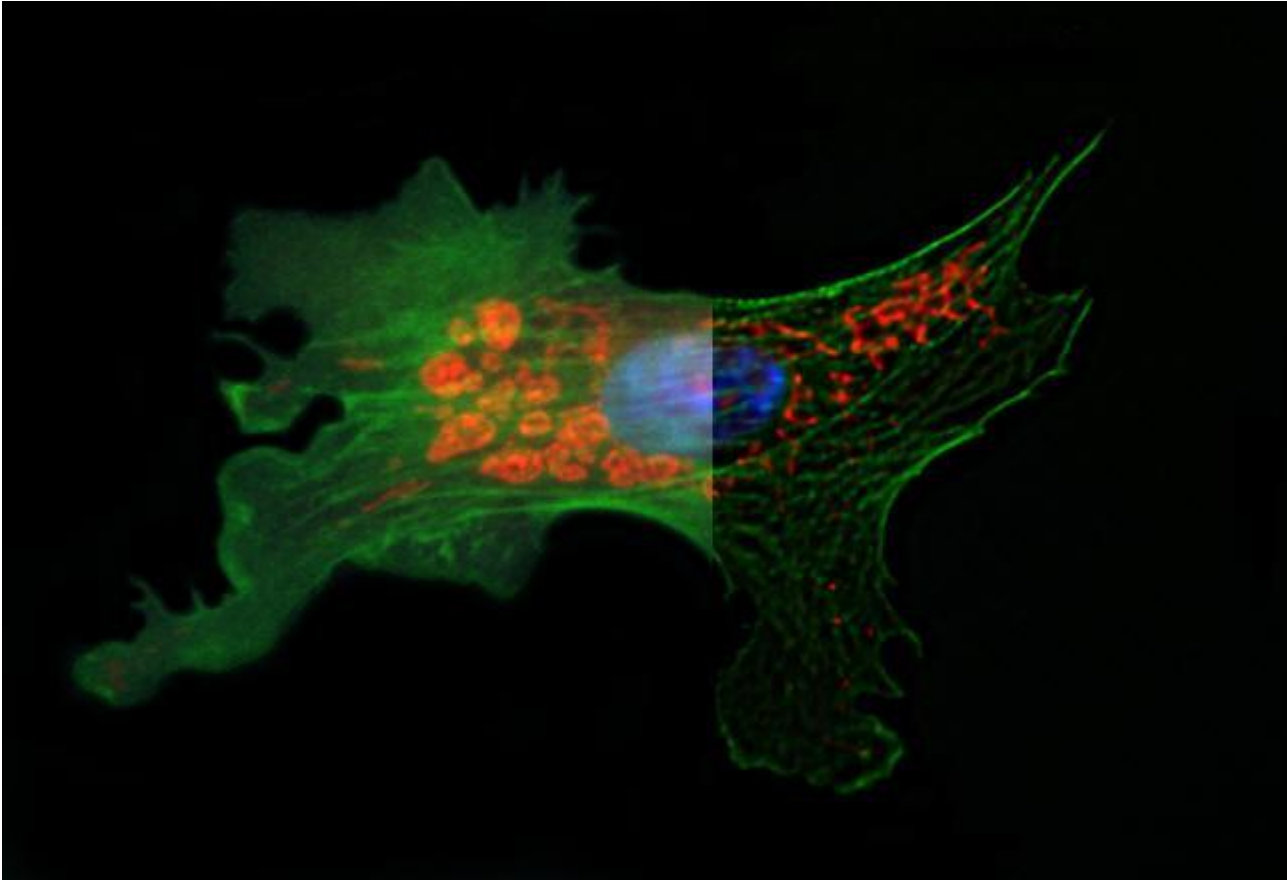
- axial intensity distributions for a typical widefield and confocal fluorescence microscope

Deconvolution



- **convolution** implies replacing every original (sub-resolution) light source by its correspondent PSF to produce a blurry image
- **deconvolution** (image restoration) would go the opposite way, collecting all this spread light and *putting it back* to its original location
 - > recover an image degraded by processes described by convolution

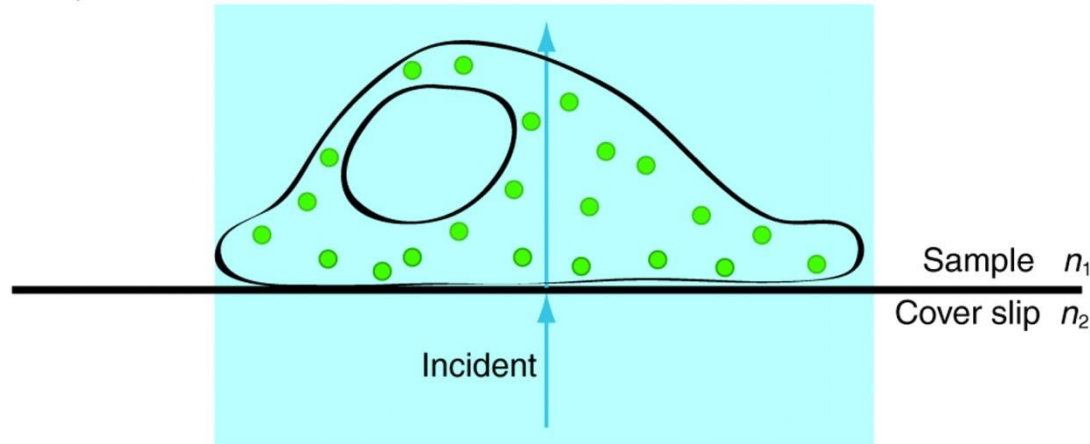
Deconvolution



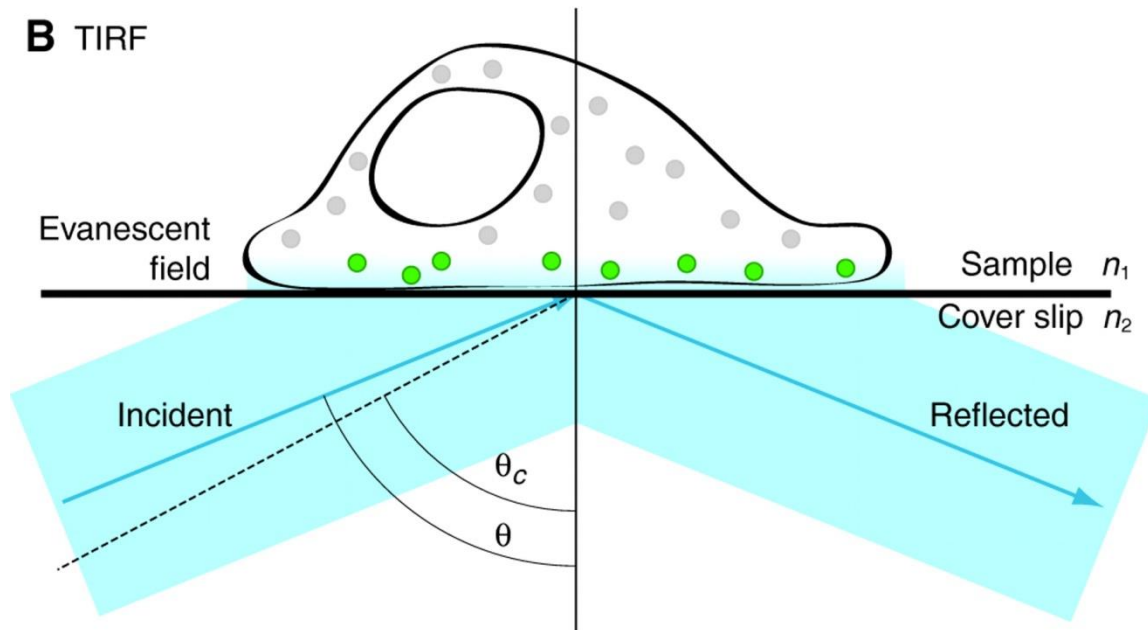
Widefield microscopy image -> *deconvolution* with experimental PSFs

TIRF microscope

A Epifluorescence



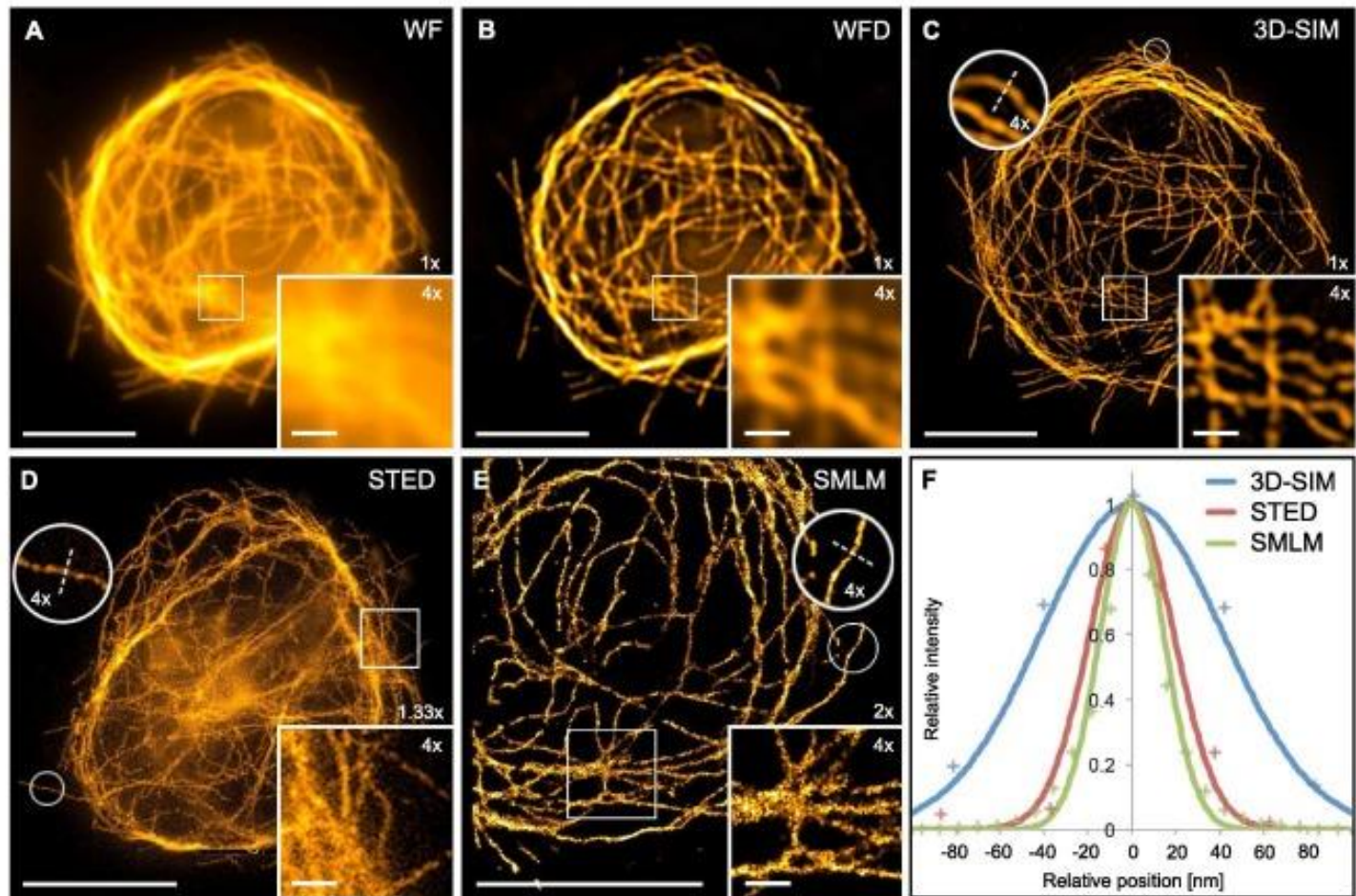
B TIRF



- a thin region of a specimen, usually less than **100 nm** can be observed (axial resolution)
- boundary to a medium of lower refractive index
- at larger angles than **critical angle** the light is reflected entirely back into the first medium -> *total internal reflection*
- **evanescent wave** selectively illuminates and excites fluorophores in a restricted region of the specimen

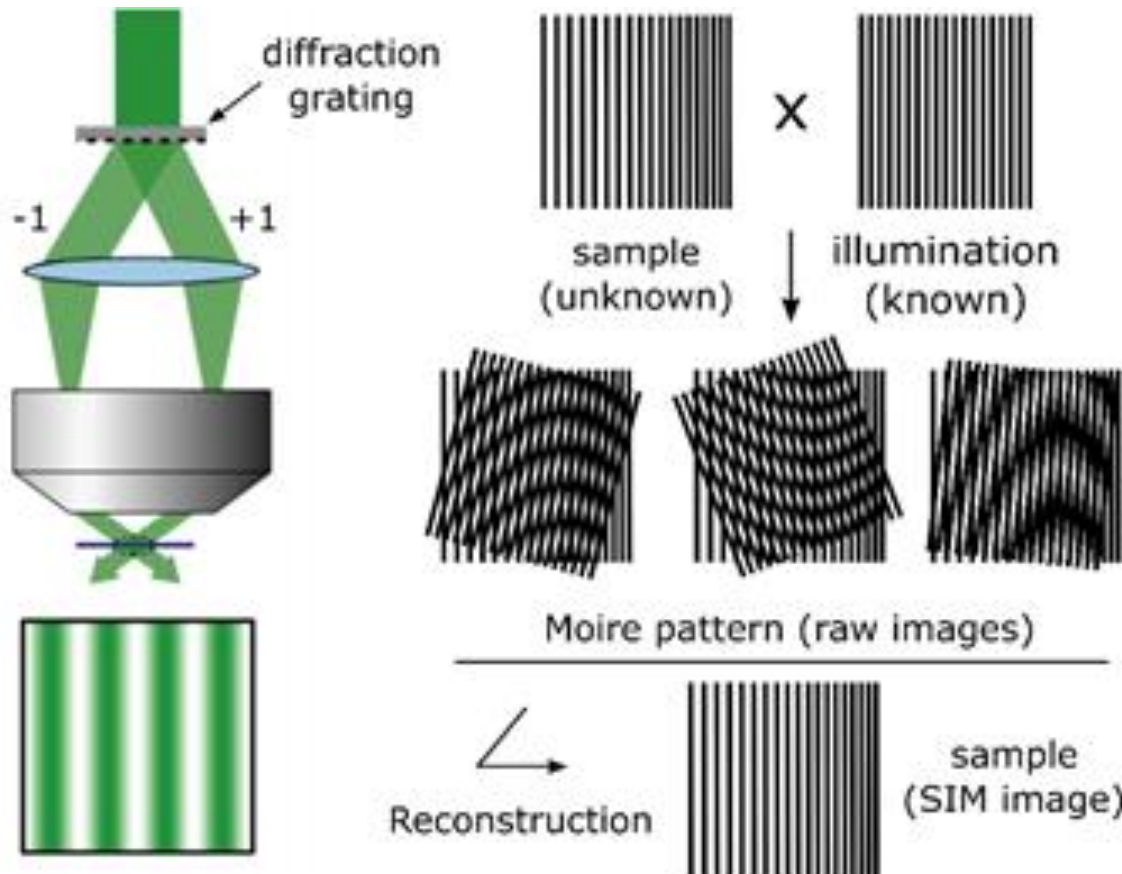
Super-resolution microscopy

Breaking the diffraction barrier:



SIM

- **Structured Illumination Microscopy** - patterned illumination to spatially modulate the fluorescence behavior of molecules within a diffraction-limited region, such that not all of them emit simultaneously, thereby achieving subdiffraction limit resolution

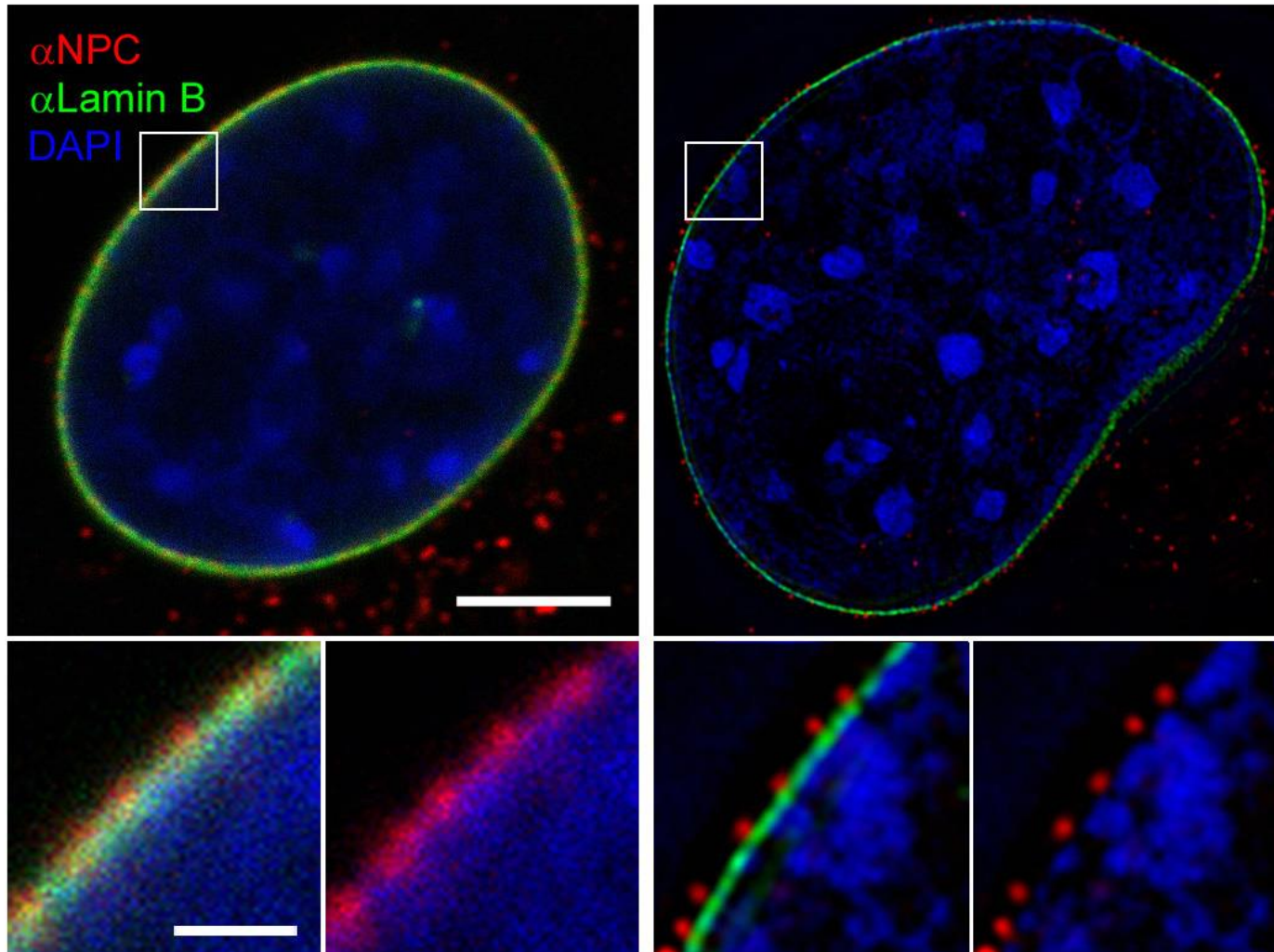


- final image is then computationally *reconstructed* from multiple snapshots collected by scanning and rotating the pattern

SIM

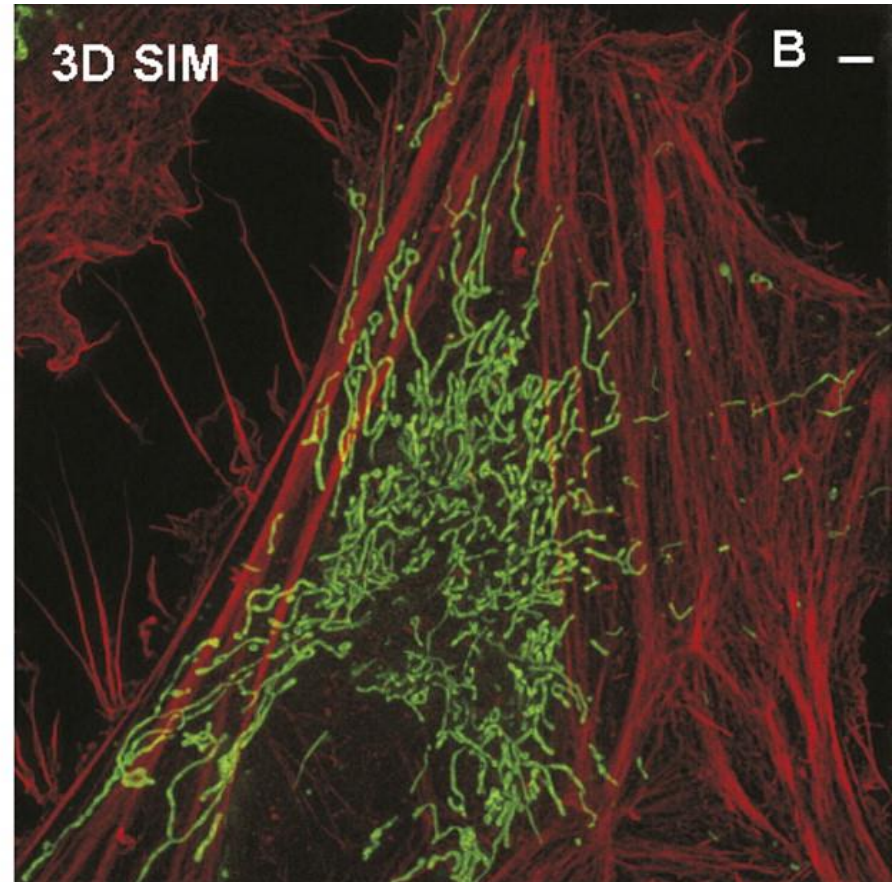
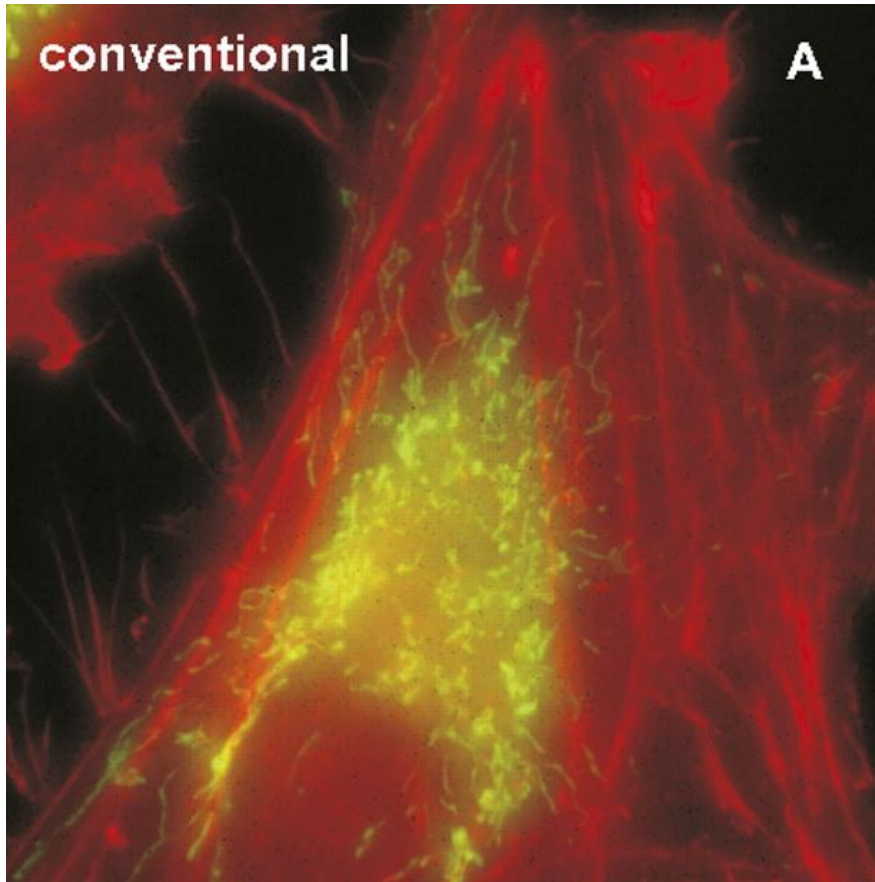
CLSM

3D-SIM



Resolution ~ 120 nm in xy and ~ 250 nm in z

Super-resolution microscopy

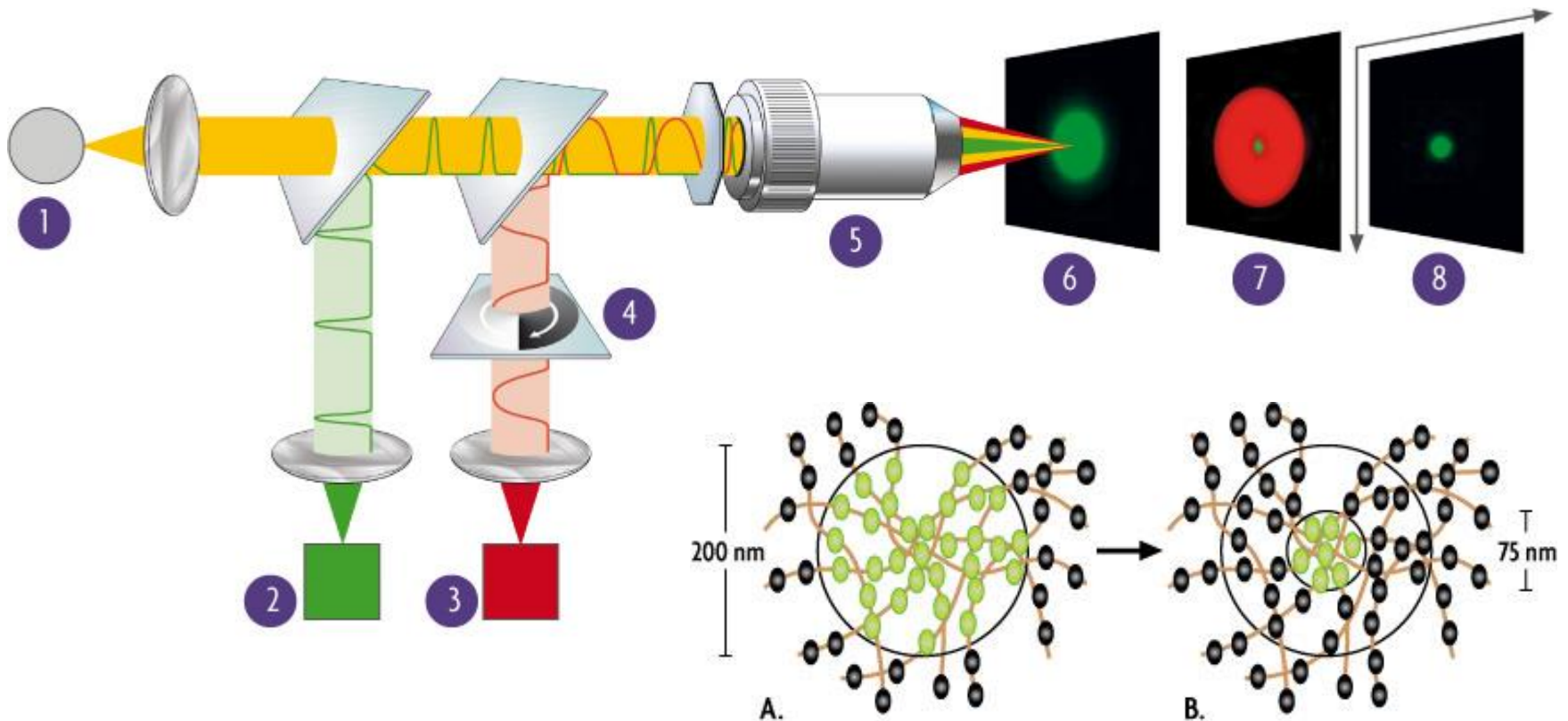


Maximum intensity projection

Resolution ~120 nm in xy and ~250 nm in z

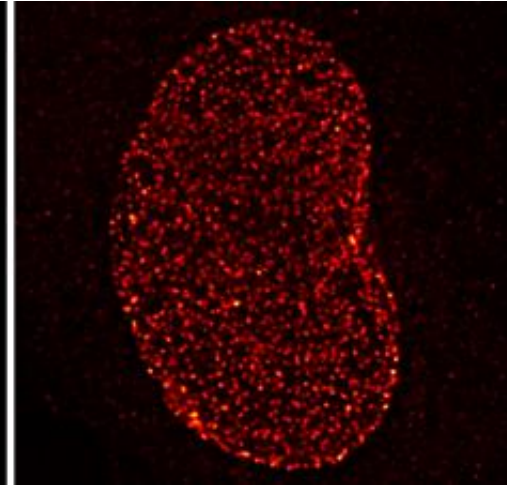
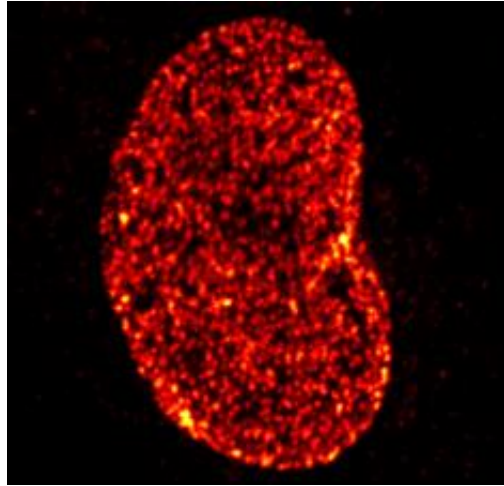
STED

- **Stimulated Emission Depletion**- uses two laser pulses, the excitation pulse for excitation of the fluorophores to their fluorescent state and the STED pulse for the de-excitation of fluorophores by means of stimulated emission, minimizing the area of illumination

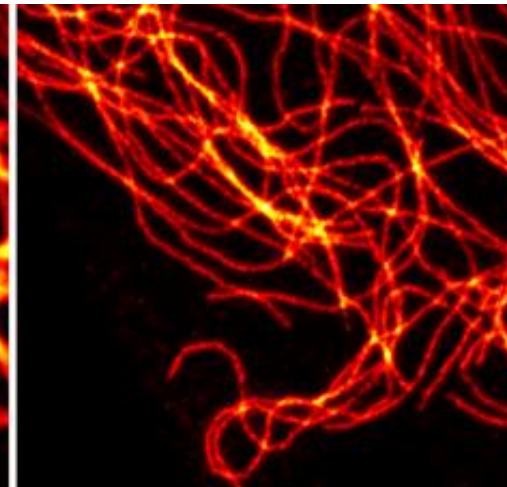
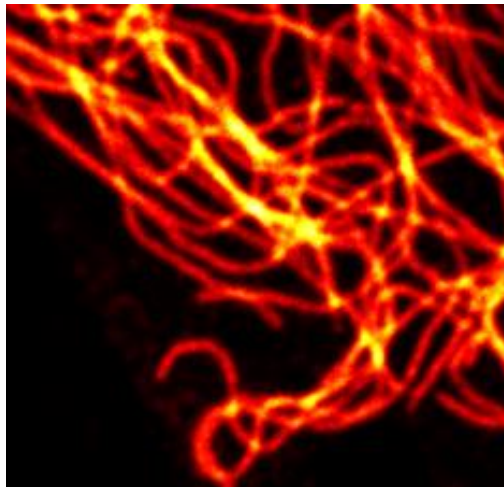


STED

Confocal

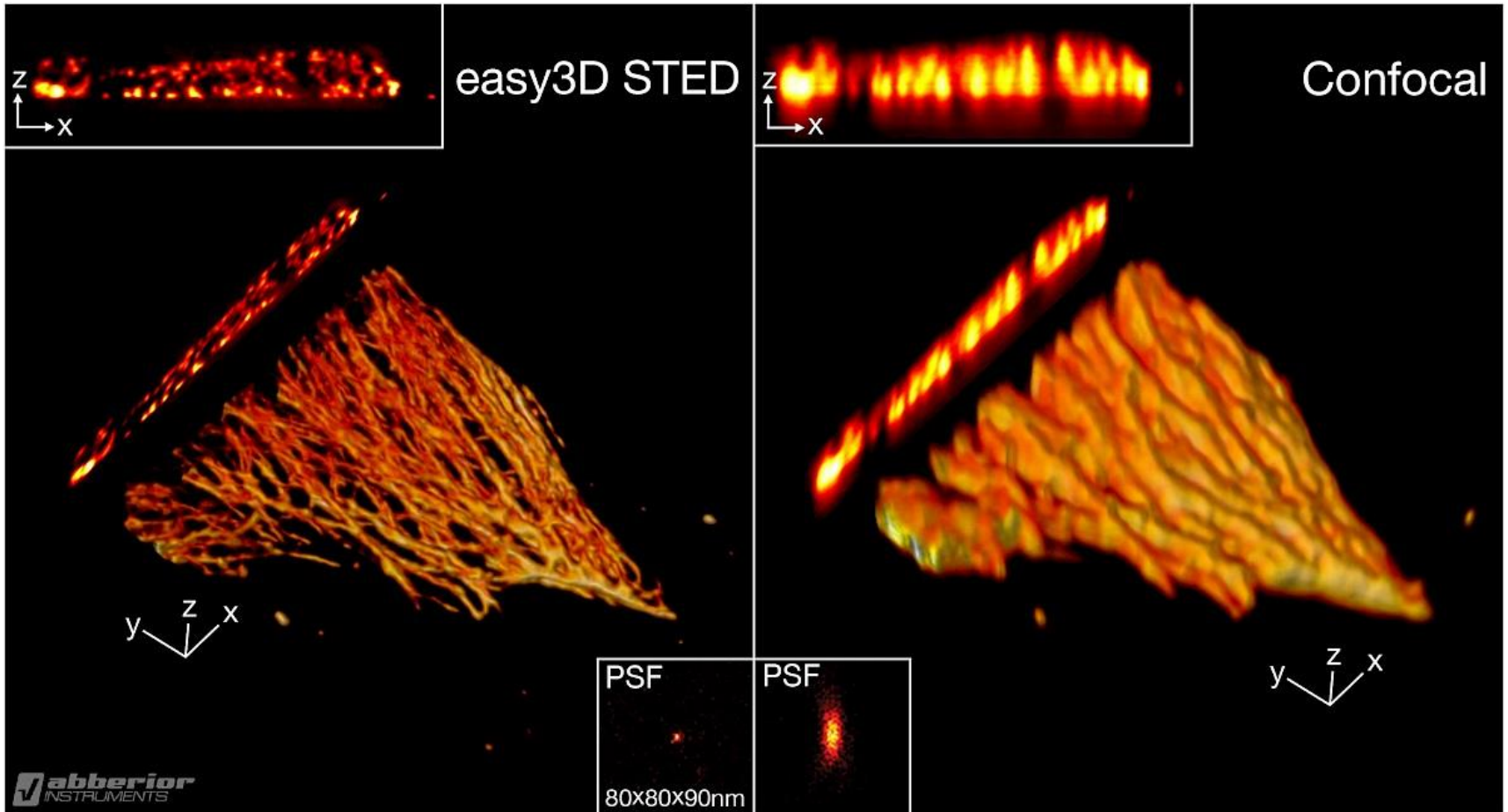


STED



Resolution ~40 nm in xy

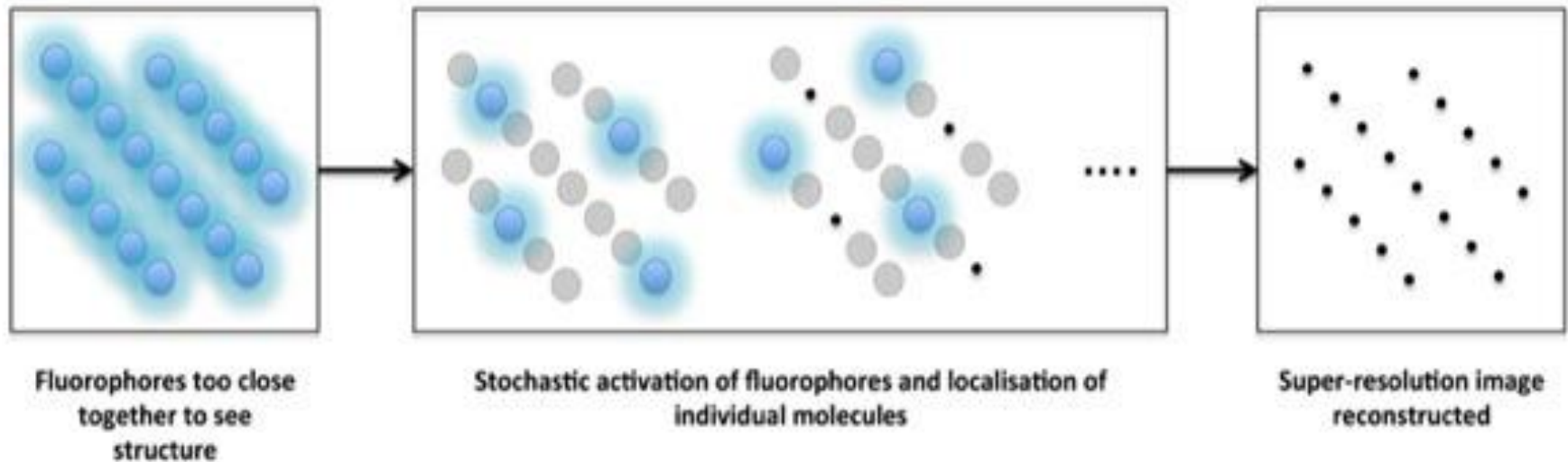
STED



Resolution ~100 nm in z

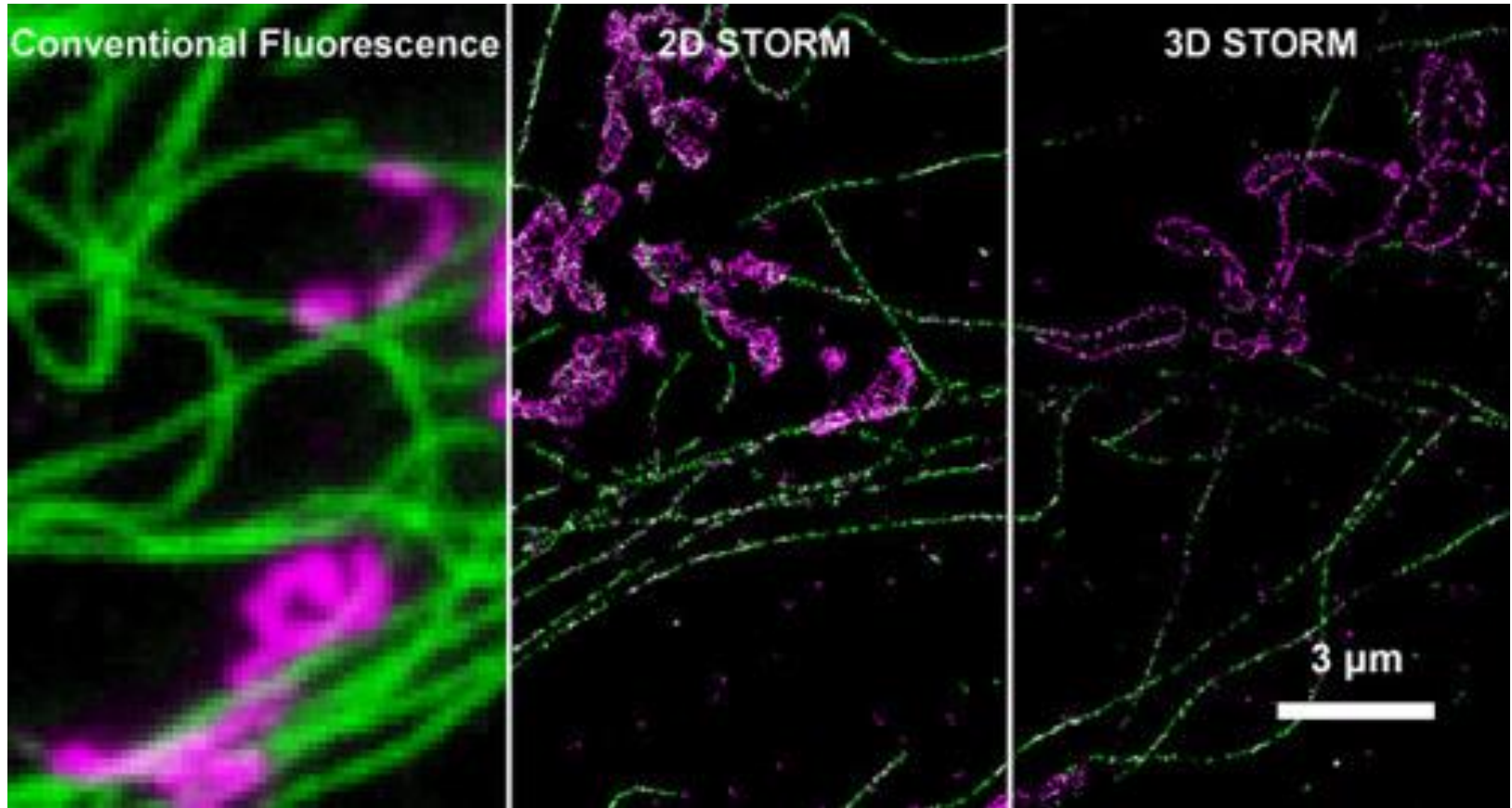
SMLM

- **Single Molecule Localization Microscopy** - super-resolution is achieved by isolating emitters and fitting their images with the point spread function (PSF)



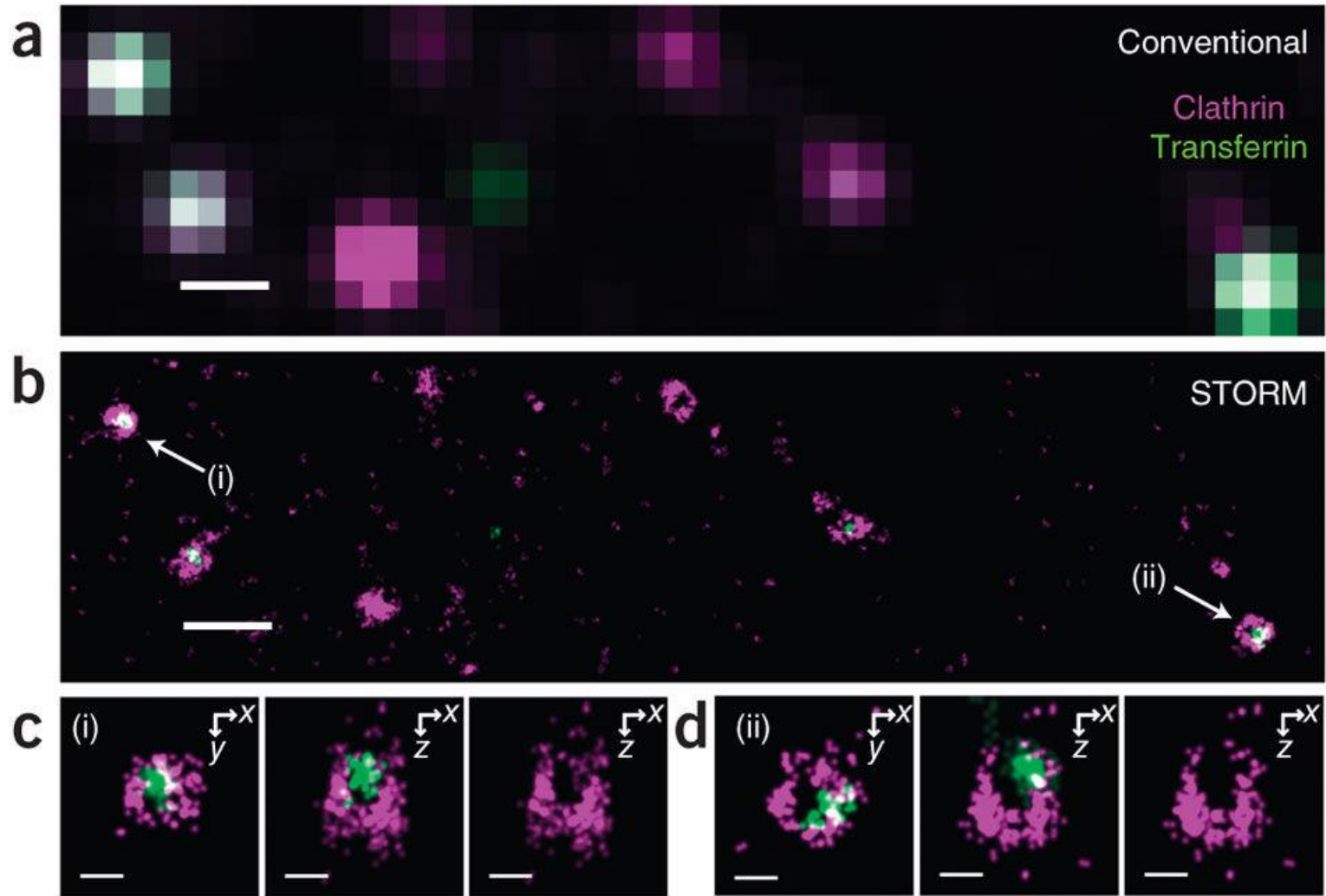
- Stochastic optical reconstruction microscopy (*STORM*)
- Photo activated localization microscopy (*PALM*)
- Fluorescence photo-activation localization microscopy (*FPALM*)
 - sequential activation and time-resolved localization of photoswitchable or photoactivatable fluorophores to create high resolution images

SMLM



Resolution ~25 nm in xy, often in TIRF setup

SMLM



dSTORM (direct STORM) – Alexa647, Alexa568

Resolution ~30 nm in xy, ~50 nm in z

Thank you for your attention!

